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Understanding [Embedded - FPGAs \(Field Programmable Gate Array\)](#)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

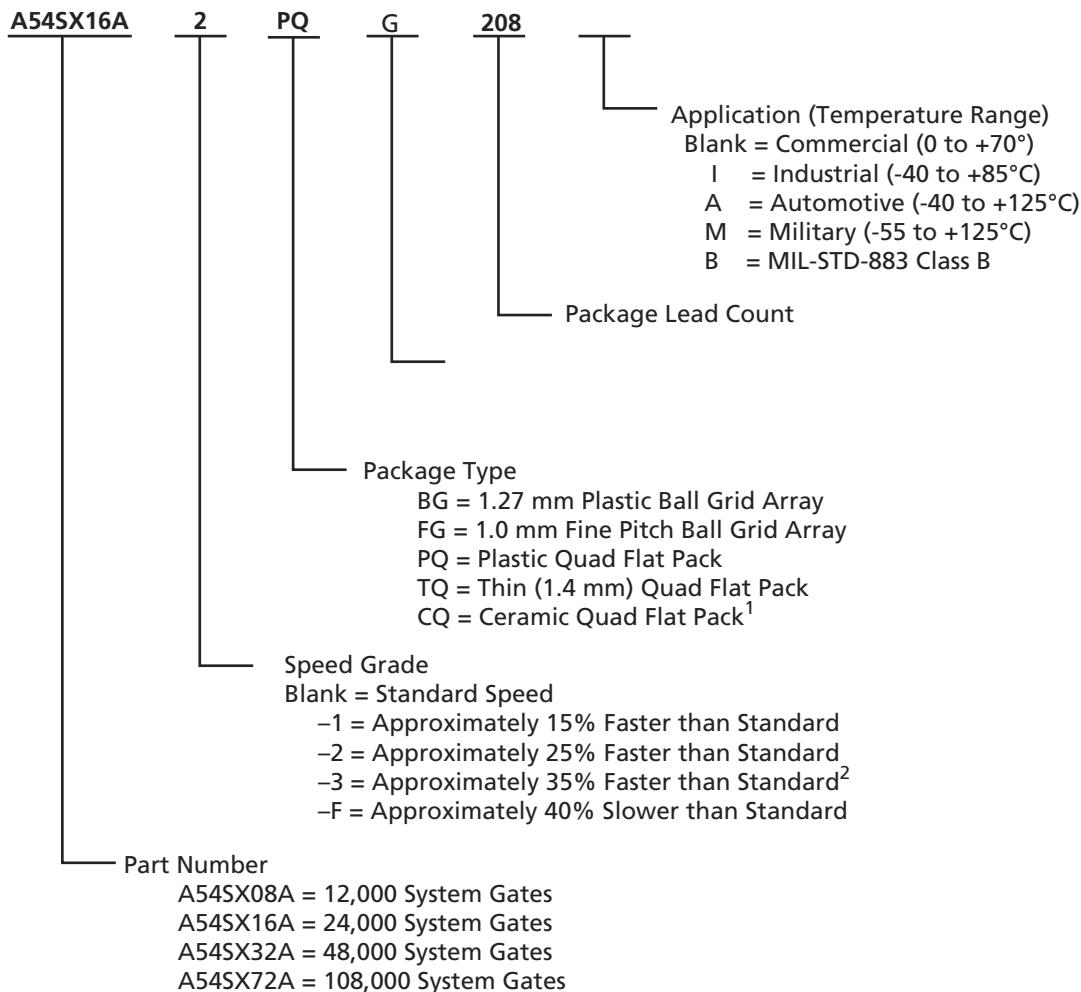
Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications,

Details

Product Status	Active
Number of LABs/CLBs	6036
Number of Logic Elements/Cells	-
Total RAM Bits	-
Number of I/O	171
Number of Gates	108000
Voltage - Supply	2.25V ~ 5.25V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 70°C (TA)
Package / Case	208-BFQFP
Supplier Device Package	208-PQFP (28x28)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/a54sx72a-2pqg208

Ordering Information



Notes:

1. For more information about the CQFP package options, refer to the HiRel SX-A datasheet.
2. All -3 speed grades have been discontinued.

Device Resources

Device	User I/Os (Including Clock Buffers)								
	208-Pin PQFP	100-Pin TQFP	144-Pin TQFP	176-Pin TQFP	329-Pin PBGA	144-Pin FBGA	256-Pin FBGA	484-Pin FBGA	
A54SX08A	130	81	113	-	-	111	-	-	
A54SX16A	175	81	113	-	-	111	180	-	
A54SX32A	174	81	113	147	249	111	203	249	
A54SX72A	171	-	-	-	-	-	203	360	

Notes: Package Definitions: PQFP = Plastic Quad Flat Pack, TQFP = Thin Quad Flat Pack, PBGA = Plastic Ball Grid Array, FBGA = Fine Pitch Ball Grid Array

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Logic Module Design

The SX-A family architecture is described as a “sea-of-modules” architecture because the entire floor of the device is covered with a grid of logic modules with virtually no chip area lost to interconnect elements or routing. The Actel SX-A family provides two types of logic modules: the register cell (R-cell) and the combinatorial cell (C-cell).

The R-cell contains a flip-flop featuring asynchronous clear, asynchronous preset, and clock enable, using the S0 and S1 lines control signals (Figure 1-2). The R-cell registers feature programmable clock polarity selectable on a register-by-register basis. This provides additional flexibility while allowing mapping of synthesized functions into the SX-A FPGA. The clock source for the R-cell can be chosen from either the hardwired clock, the routed clocks, or internal logic.

The C-cell implements a range of combinatorial functions of up to five inputs (Figure 1-3). Inclusion of the DB input and its associated inverter function allows up to 4,000

different combinatorial functions to be implemented in a single module. An example of the flexibility enabled by the inversion capability is the ability to integrate a 3-input exclusive-OR function into a single C-cell. This facilitates construction of 9-bit parity-tree functions with 1.9 ns propagation delays.

Module Organization

All C-cell and R-cell logic modules are arranged into horizontal banks called Clusters. There are two types of Clusters: Type 1 contains two C-cells and one R-cell, while Type 2 contains one C-cell and two R-cells.

Clusters are grouped together into SuperClusters (Figure 1-4 on page 1-3). SuperCluster 1 is a two-wide grouping of Type 1 Clusters. SuperCluster 2 is a two-wide group containing one Type 1 Cluster and one Type 2 Cluster. SX-A devices feature more SuperCluster 1 modules than SuperCluster 2 modules because designers typically require significantly more combinatorial logic than flip-flops.

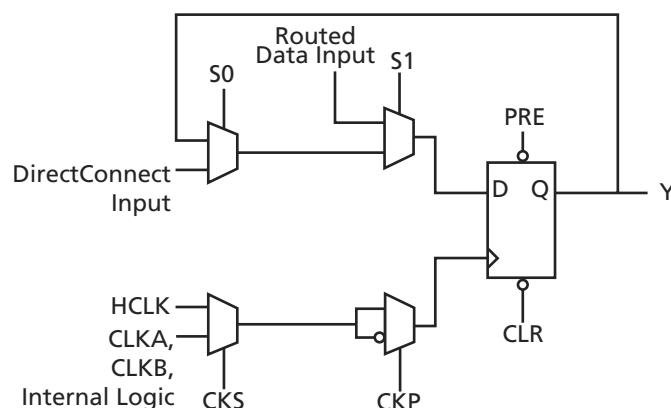


Figure 1-2 • R-Cell

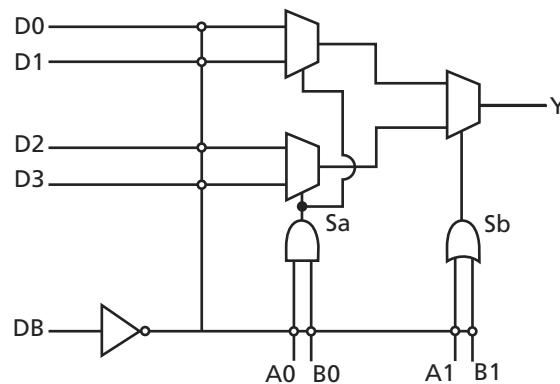


Figure 1-3 • C-Cell

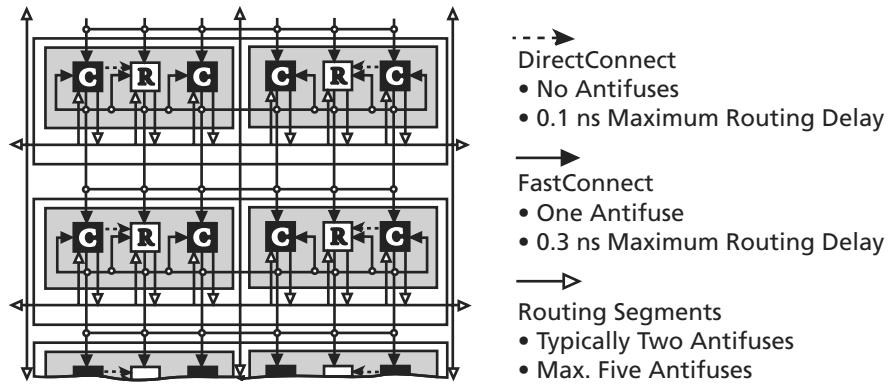


Figure 1-5 • DirectConnect and FastConnect for Type 1 SuperClusters

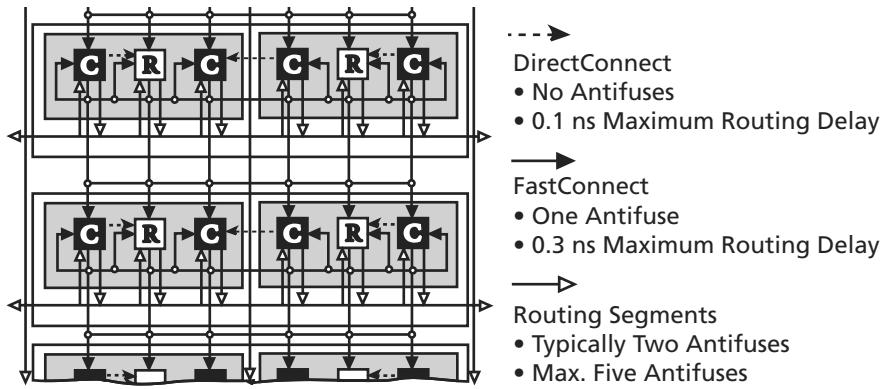


Figure 1-6 • DirectConnect and FastConnect for Type 2 SuperClusters

Clock Resources

Actel's high-drive routing structure provides three clock networks (Table 1-1). The first clock, called HCLK, is hardwired from the HCLK buffer to the clock select multiplexor (MUX) in each R-cell. HCLK cannot be connected to combinatorial logic. This provides a fast propagation path for the clock signal. If not used, this pin must be set as Low or High on the board. It must not be left floating. Figure 1-7 describes the clock circuit used for the constant load HCLK and the macros supported.

HCLK does not function until the fourth clock cycle each time the device is powered up to prevent false output levels due to any possible slow power-on-reset signal and fast start-up clock circuit. To activate HCLK from the first cycle, the TRST pin must be reserved in the Design software and the pin must be tied to GND on the board.

Two additional clocks (CLKA, CLKB) are global clocks that can be sourced from external pins or from internal logic signals within the SX-A device. CLKA and CLKB may be connected to sequential cells or to combinational logic. If CLKA or CLKB pins are not used or sourced from signals, these pins must be set as Low or High on the board. They must not be left floating. Figure 1-8 describes the CLKA

and CLKB circuit used and the macros supported in SX-A devices with the exception of A54SX72A.

In addition, the A54SX72A device provides four quadrant clocks (QCLKA, QCLKB, QCLKC, and QCLKD—corresponding to bottom-left, bottom-right, top-left, and top-right locations on the die, respectively), which can be sourced from external pins or from internal logic signals within the device. Each of these clocks can individually drive up to an entire quadrant of the chip, or they can be grouped together to drive multiple quadrants (Figure 1-9 on page 1-6). QCLK pins can function as user I/O pins. If not used, the QCLK pins must be tied Low or High on the board and must not be left floating.

For more information on how to use quadrant clocks in the A54SX72A device, refer to the *Global Clock Networks in Actel's Antifuse Devices* and *Using A54SX72A and RT54SX72S Quadrant Clocks* application notes.

The CLKA, CLKB, and QCLK circuits for A54SX72A as well as the macros supported are shown in Figure 1-10 on page 1-6. Note that bidirectional clock buffers are only available in A54SX72A. For more information, refer to the "Pin Description" section on page 1-15.

Table 1-1 • SX-A Clock Resources

	A54SX08A	A54SX16A	A54SX32A	A54SX72A
Routed Clocks (CLKA, CLKB)	2	2	2	2
Hardwired Clocks (HCLK)	1	1	1	1
Quadrant Clocks (QCLKA, QCLKB, QCLKC, QCLKD)	0	0	0	4

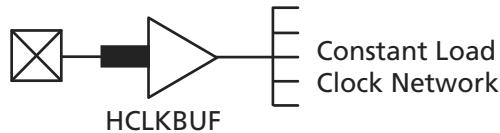


Figure 1-7 • SX-A HCLK Clock Buffer

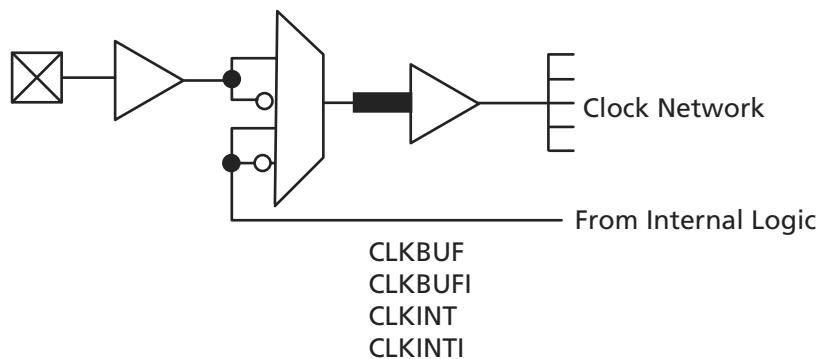


Figure 1-8 • SX-A Routed Clock Buffer

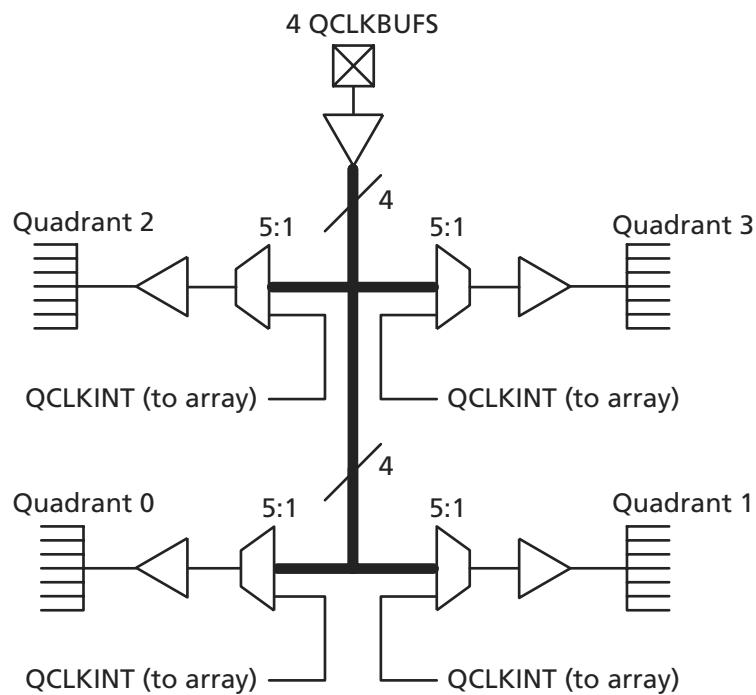


Figure 1-9 • SX-A QCLK Architecture

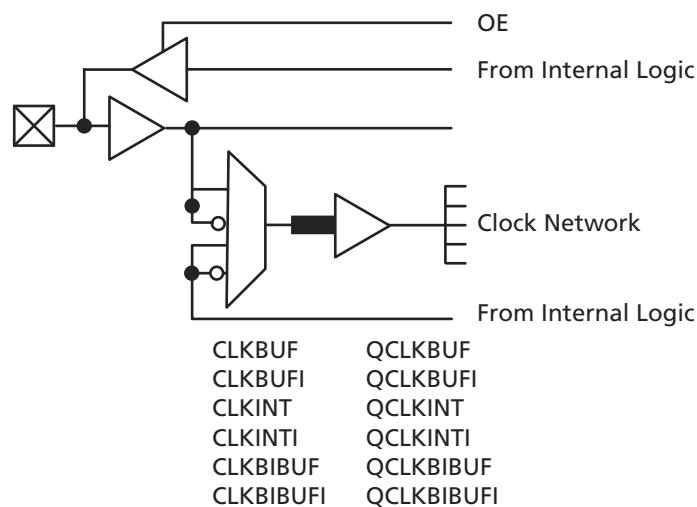


Figure 1-10 • A54SX72A Routed Clock and QCLK Buffer

Power-Up/Down and Hot Swapping

SX-A I/Os are configured to be hot-swappable, with the exception of 3.3 V PCI. During power-up/down (or partial up/down), all I/Os are tristated. V_{CCA} and V_{CCI} do not have to be stable during power-up/down, and can be powered up/down in any order. When the SX-A device is plugged into an electrically active system, the device will not degrade the reliability of or cause damage to the host system. The device's output pins are driven to a high impedance state until normal chip operating conditions

are reached. Table 1-4 summarizes the V_{CCA} voltage at which the I/Os behave according to the user's design for an SX-A device at room temperature for various ramp-up rates. The data reported assumes a linear ramp-up profile to 2.5 V. For more information on power-up and hot-swapping, refer to the application note, *Actel SX-A and RT54SX-S Devices in Hot-Swap and Cold-Sparing Applications*.

Table 1-2 • I/O Features

Function	Description
Input Buffer Threshold Selections	<ul style="list-style-type: none"> • 5 V: PCI, TTL • 3.3 V: PCI, LVTTL • 2.5 V: LVCMOS2 (commercial only)
Flexible Output Driver	<ul style="list-style-type: none"> • 5 V: PCI, TTL • 3.3 V: PCI, LVTTL • 2.5 V: LVCMOS2 (commercial only)
Output Buffer	<p>"Hot-Swap" Capability (3.3 V PCI is not hot swappable)</p> <ul style="list-style-type: none"> • I/O on an unpowered device does not sink current • Can be used for "cold-sparing" <p>Selectable on an individual I/O basis</p> <p>Individually selectable slew rate; high slew or low slew (The default is high slew rate). The slew is only affected on the falling edge of an output. Rising edges of outputs are not affected.</p>
Power-Up	<p>Individually selectable pull-ups and pull-downs during power-up (default is to power-up in tristate)</p> <p>Enables deterministic power-up of device</p> <p>V_{CCA} and V_{CCI} can be powered in any order</p>

Table 1-3 • I/O Characteristics for All I/O Configurations

	Hot Swappable	Slew Rate Control	Power-Up Resistor
TTL, LVTTL, LVCMOS2	Yes	Yes. Only affects falling edges of outputs	Pull-up or pull-down
3.3 V PCI	No	No. High slew rate only	Pull-up or pull-down
5 V PCI	Yes	No. High slew rate only	Pull-up or pull-down

Table 1-4 • Power-Up Time at which I/Os Become Active

Supply Ramp Rate	0.25 V/ μ s	0.025 V/ μ s	5 V/ms	2.5 V/ms	0.5 V/ms	0.25 V/ms	0.1 V/ms	0.025 V/ms
Units	μ s	μ s	ms	ms	ms	ms	ms	ms
A54SX08A	10	96	0.34	0.65	2.7	5.4	12.9	50.8
A54SX16A	10	100	0.36	0.62	2.5	4.7	11.0	41.6
A54SX32A	10	100	0.46	0.74	2.8	5.2	12.1	47.2
A54SX72A	10	100	0.41	0.67	2.6	5.0	12.1	47.2

Related Documents

Application Notes

Global Clock Networks in Actel's Antifuse Devices

http://www.actel.com/documents/GlobalClk_AN.pdf

Using A54SX72A and RT54SX72S Quadrant Clocks

http://www.actel.com/documents/QCLK_AN.pdf

Implementation of Security in Actel Antifuse FPGAs

http://www.actel.com/documents/Antifuse_Security_AN.pdf

Actel eX, SX-A, and RTSX-S I/Os

http://www.actel.com/documents/AntifuseIO_AN.pdf

Actel SX-A and RT54SX-S Devices in Hot-Swap and Cold-Sparing Applications

http://www.actel.com/documents/HotSwapColdSparing_AN.pdf

Programming Antifuse Devices

http://www.actel.com/documents/AntifuseProgram_AN.pdf

Datasheets

HiRel SX-A Family FPGAs

http://www.actel.com/documents/HRSXA_DS.pdf

SX-A Automotive Family FPGAs

http://www.actel.com/documents/SXA_Auto_DS.pdf

User's Guides

Silicon Sculptor User's Guide

http://www.actel.com/documents/SiliSculptII_Sculpt3_ug.pdf

Figure 2-2 shows the 3.3 V PCI V/I curve and the minimum and maximum PCI drive characteristics of the SX-A family.

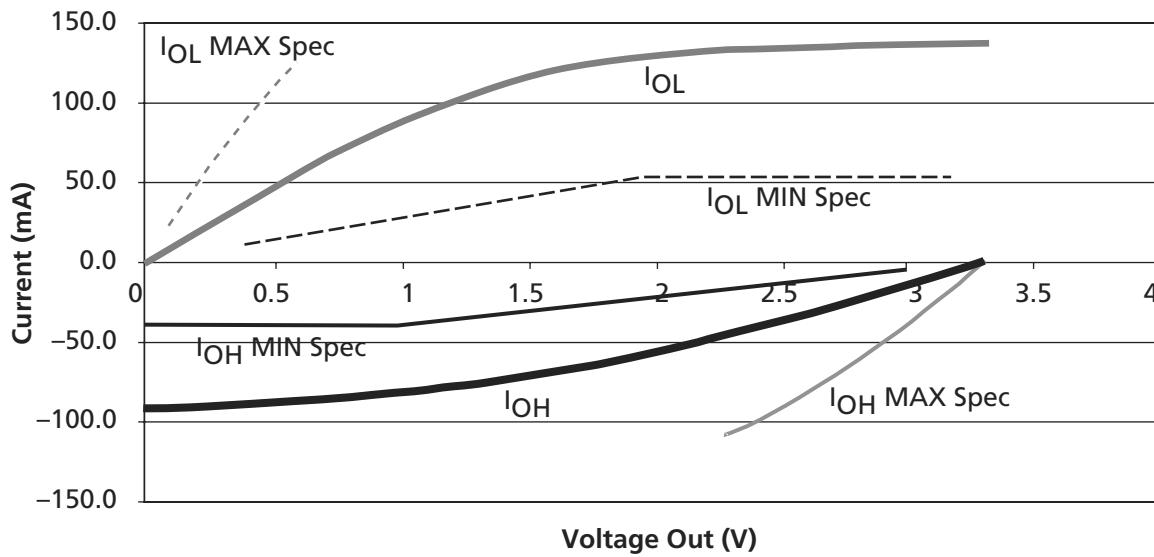


Figure 2-2 • 3.3 V PCI V/I Curve for SX-A Family

$$I_{OH} = (98.0V_{CCI}) * (V_{OUT} - V_{CCI}) * (V_{OUT} + 0.4V_{CCI})$$

for $0.7V_{CCI} < V_{OUT} < V_{CCI}$

EQ 2-3

$$I_{OL} = (256V_{CCI}) * V_{OUT} * (V_{CCI} - V_{OUT})$$

for $0V < V_{OUT} < 0.18V_{CCI}$

EQ 2-4

Power Dissipation

A critical element of system reliability is the ability of electronic devices to safely dissipate the heat generated during operation. The thermal characteristics of a circuit depend on the device and package used, the operating temperature, the operating current, and the system's ability to dissipate heat.

A complete power evaluation should be performed early in the design process to help identify potential heat-related problems in the system and to prevent the system from exceeding the device's maximum allowed junction temperature.

The actual power dissipated by most applications is significantly lower than the power the package can dissipate. However, a thermal analysis should be performed for all projects. To perform a power evaluation, follow these steps:

1. Estimate the power consumption of the application.
2. Calculate the maximum power allowed for the device and package.
3. Compare the estimated power and maximum power values.

Estimating Power Dissipation

The total power dissipation for the SX-A family is the sum of the DC power dissipation and the AC power dissipation:

$$P_{\text{Total}} = P_{\text{DC}} + P_{\text{AC}}$$

EQ 2-5

DC Power Dissipation

The power due to standby current is typically a small component of the overall power. An estimation of DC power dissipation under typical conditions is given by:

$$P_{\text{DC}} = I_{\text{Standby}} * V_{\text{CCA}}$$

EQ 2-6

Note: For other combinations of temperature and voltage settings, refer to the *eX, SX-A and RT54SX-S Power Calculator*.

AC Power Dissipation

The power dissipation of the SX-A family is usually dominated by the dynamic power dissipation. Dynamic power dissipation is a function of frequency, equivalent capacitance, and power supply voltage. The AC power dissipation is defined as follows:

$$P_{\text{AC}} = P_{\text{C-cells}} + P_{\text{R-cells}} + P_{\text{CLKA}} + P_{\text{CLKB}} + P_{\text{HCLK}} + P_{\text{Output Buffer}} + P_{\text{Input Buffer}}$$

EQ 2-7

or:

$$\begin{aligned} P_{\text{AC}} = & V_{\text{CCA}}^2 * [(m * C_{\text{EQCM}} * f_m)_{\text{C-cells}} + (m * C_{\text{EQSM}} * f_m)_{\text{R-cells}} + (n * C_{\text{EQI}} * f_n)_{\text{Input Buffer}} + (p * (C_{\text{EQO}} + C_L) * f_p)_{\text{Output Buffer}} \\ & + (0.5 * (q_1 * C_{\text{EQCR}} * f_{q1}) + (r_1 * f_{q1}))_{\text{CLKA}} + (0.5 * (q_2 * C_{\text{EQCR}} * f_{q2}) + (r_2 * f_{q2}))_{\text{CLKB}} + (0.5 * (s_1 * C_{\text{EQHV}} * f_{s1}) + \\ & (C_{\text{EQHF}} * f_{s1}))_{\text{HCLK}}] \end{aligned}$$

EQ 2-8

Where:

C_{EQCM} = Equivalent capacitance of combinatorial modules (C-cells) in pF

C_{EQSM} = Equivalent capacitance of sequential modules (R-Cells) in pF

C_{EQI} = Equivalent capacitance of input buffers in pF

C_{EQO} = Equivalent capacitance of output buffers in pF

C_{EQCR} = Equivalent capacitance of CLKA/B in pF

C_{EQHV} = Variable capacitance of HCLK in pF

C_{EQHF} = Fixed capacitance of HCLK in pF

C_L = Output lead capacitance in pF

f_m = Average logic module switching rate in MHz

f_n = Average input buffer switching rate in MHz

f_p = Average output buffer switching rate in MHz

f_{q1} = Average CLKA rate in MHz

f_{q2} = Average CLKB rate in MHz

f_{s1} = Average HCLK rate in MHz

m = Number of logic modules switching at f_m

n = Number of input buffers switching at f_n

p = Number of output buffers switching at f_p

q_1 = Number of clock loads on CLKA

q_2 = Number of clock loads on CLKB

r_1 = Fixed capacitance due to CLKA

r_2 = Fixed capacitance due to CLKB

s_1 = Number of clock loads on HCLK

x = Number of I/Os at logic low

y = Number of I/Os at logic high

Table 2-11 • CEQ Values for SX-A Devices

	A54SX08A	A54SX16A	A54SX32A	A54SX72A
Combinatorial modules (C_{EQCM})	1.70 pF	2.00 pF	2.00 pF	1.80 pF
Sequential modules (C_{EQCM})	1.50 pF	1.50 pF	1.30 pF	1.50 pF
Input buffers (C_{EQI})	1.30 pF	1.30 pF	1.30 pF	1.30 pF
Output buffers (C_{EQO})	7.40 pF	7.40 pF	7.40 pF	7.40 pF
Routed array clocks (C_{EQCR})	1.05 pF	1.05 pF	1.05 pF	1.05 pF
Dedicated array clocks – variable (C_{EQHV})	0.85 pF	0.85 pF	0.85 pF	0.85 pF
Dedicated array clocks – fixed (C_{EQHF})	30.00 pF	55.00 pF	110.00 pF	240.00 pF
Routed array clock A (r_1)	35.00 pF	50.00 pF	90.00 pF	310.00 pF

To determine the heat sink's thermal performance, use the following equation:

$$\theta_{JA(TOTAL)} = \theta_{JC} + \theta_{CS} + \theta_{SA}$$

EQ 2-14

where:

$$\theta_{CS} = 0.37^{\circ}\text{C}/\text{W}$$

= thermal resistance of the interface material between the case and the heat sink, usually provided by the thermal interface manufacturer

$$\theta_{SA} = \text{thermal resistance of the heat sink in } ^{\circ}\text{C}/\text{W}$$

$$\theta_{SA} = \theta_{JA(TOTAL)} - \theta_{JC} - \theta_{CS}$$

EQ 2-15

$$\theta_{SA} = 13.33^{\circ}\text{C}/\text{W} - 3.20^{\circ}\text{C}/\text{W} - 0.37^{\circ}\text{C}/\text{W}$$

$$\theta_{SA} = 9.76^{\circ}\text{C}/\text{W}$$

A heat sink with a thermal resistance of $9.76^{\circ}\text{C}/\text{W}$ or better should be used. Thermal resistance of heat sinks is a function of airflow. The heat sink performance can be significantly improved with the presence of airflow.

Carefully estimating thermal resistance is important in the long-term reliability of an Actel FPGA. Design engineers should always correlate the power consumption of the device with the maximum allowable power dissipation of the package selected for that device, using the provided thermal resistance data.

Note: The values may vary depending on the application.

Table 2-18 • A54SX08A Timing Characteristics
 (Worst-Case Commercial Conditions $V_{CCA} = 2.25\text{ V}$, $V_{CCI} = 2.3\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	-2 Speed		-1 Speed		Std. Speed		-F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
2.5 V LVCMOS Output Module Timing^{1,2}										
t_{DLH}	Data-to-Pad Low to High	3.9	4.4	5.2	7.2	ns				
t_{DHL}	Data-to-Pad High to Low	3.0	3.4	3.9	5.5	ns				
t_{DHLS}	Data-to-Pad High to Low—low slew	13.3	15.1	17.7	24.8	ns				
t_{ENZL}	Enable-to-Pad, Z to L	2.8	3.2	3.7	5.2	ns				
t_{ENZLS}	Data-to-Pad, Z to L—low slew	13.7	15.5	18.2	25.5	ns				
t_{ENZH}	Enable-to-Pad, Z to H	3.9	4.4	5.2	7.2	ns				
t_{ENLZ}	Enable-to-Pad, L to Z	2.5	2.8	3.3	4.7	ns				
t_{ENHZ}	Enable-to-Pad, H to Z	3.0	3.4	3.9	5.5	ns				
d_{TLH}^3	Delta Low to High	0.037	0.043	0.051	0.071	ns/pF				
d_{THL}^3	Delta High to Low	0.017	0.023	0.023	0.037	ns/pF				
d_{THLS}^3	Delta High to Low—low slew	0.06	0.071	0.086	0.117	ns/pF				

Note:

1. Delays based on 35 pF loading.
2. The equivalent I/O Attribute Editor settings for 2.5 V LVCMOS is 2.5 V LVTTL in the software.
3. To obtain the slew rate, substitute the appropriate Delta value, load capacitance, and the V_{CCI} value into the following equation:

$$\text{Slew Rate [V/ns]} = (0.1 * V_{CCI} - 0.9 * V_{CCI}) / (C_{load} * d_{T[LH|HL|HLS]})$$
 where C_{load} is the load capacitance driven by the I/O in pF.
 $d_{T[LH|HL|HLS]}$ is the worst case delta value from the datasheet in ns/pF.

Table 2-21 • A54SX16A Timing Characteristics
 (Worst-Case Commercial Conditions, $V_{CCA} = 2.25\text{ V}$, $V_{CCI} = 3.0\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	-3 Speed¹		-2 Speed		-1 Speed		Std. Speed	-F Speed	Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
C-Cell Propagation Delays²										
t_{PD}	Internal Array Module	0.9	1.0	1.2	1.4	1.6	1.8	1.9	ns	
Predicted Routing Delays³										
t_{DC}	FO = 1 Routing Delay, Direct Connect	0.1	0.1	0.1	0.1	0.1	0.1	0.1	ns	
t_{FC}	FO = 1 Routing Delay, Fast Connect	0.3	0.3	0.3	0.4	0.4	0.4	0.6	ns	
t_{RD1}	FO = 1 Routing Delay	0.3	0.3	0.4	0.5	0.5	0.5	0.6	ns	
t_{RD2}	FO = 2 Routing Delay	0.4	0.5	0.5	0.6	0.6	0.6	0.8	ns	
t_{RD3}	FO = 3 Routing Delay	0.5	0.6	0.7	0.8	0.8	0.8	1.1	ns	
t_{RD4}	FO = 4 Routing Delay	0.7	0.8	0.9	1.0	1.0	1.0	1.4	ns	
t_{RD8}	FO = 8 Routing Delay	1.2	1.4	1.5	1.8	1.8	1.8	2.5	ns	
t_{RD12}	FO = 12 Routing Delay	1.7	2	2.2	2.6	2.6	2.6	3.6	ns	
R-Cell Timing										
t_{RCO}	Sequential Clock-to-Q	0.6	0.7	0.8	0.9	0.9	1.0	1.3	ns	
t_{CLR}	Asynchronous Clear-to-Q	0.5	0.6	0.6	0.8	0.8	1.0	1.0	ns	
t_{PRESET}	Asynchronous Preset-to-Q	0.7	0.8	0.8	1.0	1.0	1.4	1.4	ns	
t_{SUD}	Flip-Flop Data Input Set-Up	0.7	0.8	0.9	1.0	1.0	1.4	1.4	ns	
t_{HD}	Flip-Flop Data Input Hold	0.0	0.0	0.0	0.0	0.0	0.0	0.0	ns	
t_{WASYN}	Asynchronous Pulse Width	1.3	1.5	1.6	1.9	1.9	2.7	2.7	ns	
$t_{RECASYN}$	Asynchronous Recovery Time	0.3	0.4	0.4	0.5	0.5	0.7	0.7	ns	
t_{HASYN}	Asynchronous Removal Time	0.3	0.3	0.3	0.4	0.4	0.6	0.6	ns	
t_{MPW}	Clock Minimum Pulse Width	1.4	1.7	1.9	2.2	2.2	3.0	3.0	ns	
Input Module Propagation Delays										
t_{INYH}	Input Data Pad to Y High 2.5 V LVC MOS	0.5	0.6	0.7	0.8	0.8	1.1	1.1	ns	
t_{INYL}	Input Data Pad to Y Low 2.5 V LVC MOS	0.8	0.9	1.0	1.1	1.1	1.6	1.6	ns	
t_{INYH}	Input Data Pad to Y High 3.3 V PCI	0.5	0.6	0.6	0.7	0.7	1.0	1.0	ns	
t_{INYL}	Input Data Pad to Y Low 3.3 V PCI	0.7	0.8	0.9	1.0	1.0	1.4	1.4	ns	
t_{INYH}	Input Data Pad to Y High 3.3 V LV TTL	0.7	0.7	0.8	1.0	1.0	1.4	1.4	ns	
t_{INYL}	Input Data Pad to Y Low 3.3 V LV TTL	0.9	1.1	1.2	1.4	1.4	2.0	2.0	ns	

Notes:

1. All -3 speed grades have been discontinued.
2. For dual-module macros, use $t_{PD} + t_{RD1} + t_{PDn}$, $t_{RCO} + t_{RD1} + t_{PDn}$, or $t_{PD1} + t_{RD1} + t_{SUD}$, whichever is appropriate.
3. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.

Table 2-28 • A54SX32A Timing Characteristics
 (Worst-Case Commercial Conditions, $V_{CCA} = 2.25\text{ V}$, $V_{CCI} = 3.0\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	-3 Speed¹	-2 Speed	-1 Speed	Std. Speed	-F Speed	Units
		Min.	Max.	Min.	Max.	Min.	
C-Cell Propagation Delays²							
t_{PD}	Internal Array Module	0.8	0.9	1.1	1.2	1.7	ns
Predicted Routing Delays³							
t_{DC}	FO = 1 Routing Delay, Direct Connect	0.1	0.1	0.1	0.1	0.1	ns
t_{FC}	FO = 1 Routing Delay, Fast Connect	0.3	0.3	0.3	0.4	0.6	ns
t_{RD1}	FO = 1 Routing Delay	0.3	0.3	0.4	0.5	0.6	ns
t_{RD2}	FO = 2 Routing Delay	0.4	0.5	0.5	0.6	0.8	ns
t_{RD3}	FO = 3 Routing Delay	0.5	0.6	0.7	0.8	1.1	ns
t_{RD4}	FO = 4 Routing Delay	0.7	0.8	0.9	1.0	1.4	ns
t_{RD8}	FO = 8 Routing Delay	1.2	1.4	1.5	1.8	2.5	ns
t_{RD12}	FO = 12 Routing Delay	1.7	2.0	2.2	2.6	3.6	ns
R-Cell Timing							
t_{RCO}	Sequential Clock-to-Q	0.6	0.7	0.8	0.9	1.3	ns
t_{CLR}	Asynchronous Clear-to-Q	0.5	0.6	0.6	0.8	1.0	ns
t_{PRESET}	Asynchronous Preset-to-Q	0.6	0.7	0.7	0.9	1.2	ns
t_{SUD}	Flip-Flop Data Input Set-Up	0.6	0.7	0.8	0.9	1.2	ns
t_{HD}	Flip-Flop Data Input Hold	0.0	0.0	0.0	0.0	0.0	ns
t_{WASYN}	Asynchronous Pulse Width	1.2	1.4	1.5	1.8	2.5	ns
$t_{RECASYN}$	Asynchronous Recovery Time	0.3	0.4	0.4	0.5	0.7	ns
t_{HASYN}	Asynchronous Removal Time	0.3	0.3	0.3	0.4	0.6	ns
t_{MPW}	Clock Pulse Width	1.4	1.6	1.8	2.1	2.9	ns
Input Module Propagation Delays							
t_{INYH}	Input Data Pad to Y High 2.5 V LVC MOS	0.6	0.7	0.8	0.9	1.2	ns
t_{INYL}	Input Data Pad to Y Low 2.5 V LVC MOS	1.2	1.3	1.5	1.8	2.5	ns
t_{INYH}	Input Data Pad to Y High 3.3 V PCI	0.5	0.6	0.6	0.7	1.0	ns
t_{INYL}	Input Data Pad to Y Low 3.3 V PCI	0.6	0.7	0.8	0.9	1.3	ns
t_{INYH}	Input Data Pad to Y High 3.3 V LV TTL	0.8	0.9	1.0	1.2	1.6	ns
t_{INYL}	Input Data Pad to Y Low 3.3 V LV TTL	1.4	1.6	1.8	2.2	3.0	ns

Notes:

1. All -3 speed grades have been discontinued.
2. For dual-module macros, use $t_{PD} + t_{RD1} + t_{PDn}$, $t_{RCO} + t_{RD1} + t_{PDn}$, or $t_{PD1} + t_{RD1} + t_{SUD}$, whichever is appropriate.
3. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.

Table 2-33 • A54SX32A Timing Characteristics
 (Worst-Case Commercial Conditions $V_{CCA} = 2.25\text{ V}$, $V_{CCI} = 3.0\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	-3 Speed¹	-2 Speed	-1 Speed	Std. Speed	-F Speed	Units
		Min.	Max.	Min.	Max.	Min.	
3.3 V PCI Output Module Timing²							
t_{DLH}	Data-to-Pad Low to High	1.9	2.2	2.4	2.9	4.0	ns
t_{DHL}	Data-to-Pad High to Low	2.0	2.3	2.6	3.1	4.3	ns
t_{ENZL}	Enable-to-Pad, Z to L	1.4	1.7	1.9	2.2	3.1	ns
t_{ENZH}	Enable-to-Pad, Z to H	1.9	2.2	2.4	2.9	4.0	ns
t_{ENLZ}	Enable-to-Pad, L to Z	2.5	2.8	3.2	3.8	5.3	ns
t_{ENHZ}	Enable-to-Pad, H to Z	2.0	2.3	2.6	3.1	4.3	ns
d_{TLH}^3	Delta Low to High	0.025	0.03	0.03	0.04	0.045	ns/pF
d_{THL}^3	Delta High to Low	0.015	0.015	0.015	0.015	0.025	ns/pF
3.3 V LVTTL Output Module Timing⁴							
t_{DLH}	Data-to-Pad Low to High	2.6	3.0	3.4	4.0	5.6	ns
t_{DHL}	Data-to-Pad High to Low	2.6	3.0	3.3	3.9	5.5	ns
t_{DHLS}	Data-to-Pad High to Low—low slew	9.0	10.4	11.8	13.8	19.3	ns
t_{ENZL}	Enable-to-Pad, Z to L	2.2	2.6	2.9	3.4	4.8	ns
t_{ENZLS}	Enable-to-Pad, Z to L—low slew	15.8	18.9	21.3	25.4	34.9	ns
t_{ENZH}	Enable-to-Pad, Z to H	2.6	3.0	3.4	4.0	5.6	ns
t_{ENLZ}	Enable-to-Pad, L to Z	2.9	3.3	3.7	4.4	6.2	ns
t_{ENHZ}	Enable-to-Pad, H to Z	2.6	3.0	3.3	3.9	5.5	ns
d_{TLH}^3	Delta Low to High	0.025	0.03	0.03	0.04	0.045	ns/pF
d_{THL}^3	Delta High to Low	0.015	0.015	0.015	0.015	0.025	ns/pF
d_{THLS}^3	Delta High to Low—low slew	0.053	0.053	0.067	0.073	0.107	ns/pF

Notes:

1. All -3 speed grades have been discontinued.
2. Delays based on 10 pF loading and 25 Ω resistance.
3. To obtain the slew rate, substitute the appropriate Delta value, load capacitance, and the V_{CCI} value into the following equation:

$$\text{Slew Rate [V/ns]} = (0.1 * V_{CCI} - 0.9 * V_{CCI}) / (C_{load} * d_{T[LH|HL|HLS]})$$

where C_{load} is the load capacitance driven by the I/O in pF.
 $d_{T[LH|HL|HLS]}$ is the worst case delta value from the datasheet in ns/pF.
4. Delays based on 35 pF loading.

Table 2-38 • A54SX72A Timing Characteristics
 (Worst-Case Commercial Conditions $V_{CCA} = 2.25\text{ V}$, $V_{CCI} = 4.75\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	-3 Speed*	-2 Speed	-1 Speed	Std. Speed	-F Speed	Units
		Min.	Max.	Min.	Max.	Min.	
Dedicated (Hardwired) Array Clock Networks							
t_{HCKH}	Input Low to High (Pad to R-cell Input)	1.6	1.8	2.1	2.4	3.8	ns
t_{HCKL}	Input High to Low (Pad to R-cell Input)	1.6	1.9	2.1	2.5	3.8	ns
t_{HPWH}	Minimum Pulse Width High	1.5	1.7	2.0	2.3	3.2	ns
t_{HPWL}	Minimum Pulse Width Low	1.5	1.7	2.0	2.3	3.2	ns
t_{HCKSW}	Maximum Skew	1.4	1.6	1.8	2.1	3.3	ns
t_{HP}	Minimum Period	3.0	3.4	4.0	4.6	6.4	ns
f_{HMAX}	Maximum Frequency	333	294	250	217	156	MHz
Routed Array Clock Networks							
t_{RCKH}	Input Low to High (Light Load) (Pad to R-cell Input)	2.3	2.6	3.0	3.5	4.9	ns
t_{RCKL}	Input High to Low (Light Load) (Pad to R-cell Input)	2.8	3.2	3.6	4.3	6.0	ns
t_{RCKH}	Input Low to High (50% Load) (Pad to R-cell Input)	2.5	2.9	3.2	3.8	5.3	ns
t_{RCKL}	Input High to Low (50% Load) (Pad to R-cell Input)	3.0	3.4	3.9	4.6	6.4	ns
t_{RCKH}	Input Low to High (100% Load) (Pad to R-cell Input)	2.6	3.0	3.4	3.9	5.5	ns
t_{RCKL}	Input High to Low (100% Load) (Pad to R-cell Input)	3.2	3.6	4.1	4.8	6.8	ns
t_{RPWH}	Minimum Pulse Width High	1.5	1.7	2.0	2.3	3.2	ns
t_{RPWL}	Minimum Pulse Width Low	1.5	1.7	2.0	2.3	3.2	ns
t_{RCKSW}	Maximum Skew (Light Load)	1.9	2.2	2.5	3.0	4.1	ns
t_{RCKSW}	Maximum Skew (50% Load)	1.9	2.2	2.5	3.0	4.1	ns
t_{RCKSW}	Maximum Skew (100% Load)	1.9	2.2	2.5	3.0	4.1	ns
Quadrant Array Clock Networks							
t_{QCKH}	Input Low to High (Light Load) (Pad to R-cell Input)	1.2	1.4	1.6	1.8	2.6	ns
t_{QCHKL}	Input High to Low (Light Load) (Pad to R-cell Input)	1.3	1.4	1.6	1.9	2.7	ns
t_{QCKH}	Input Low to High (50% Load) (Pad to R-cell Input)	1.4	1.6	1.8	2.1	3.0	ns
t_{QCHKL}	Input High to Low (50% Load) (Pad to R-cell Input)	1.4	1.7	1.9	2.2	3.1	ns

Note: *All -3 speed grades have been discontinued.

208-Pin PQFP				
Pin Number	A54SX08A Function	A54SX16A Function	A54SX32A Function	A54SX72A Function
1	GND	GND	GND	GND
2	TDI, I/O	TDI, I/O	TDI, I/O	TDI, I/O
3	I/O	I/O	I/O	I/O
4	NC	I/O	I/O	I/O
5	I/O	I/O	I/O	I/O
6	NC	I/O	I/O	I/O
7	I/O	I/O	I/O	I/O
8	I/O	I/O	I/O	I/O
9	I/O	I/O	I/O	I/O
10	I/O	I/O	I/O	I/O
11	TMS	TMS	TMS	TMS
12	V _{CCI}	V _{CCI}	V _{CCI}	V _{CCI}
13	I/O	I/O	I/O	I/O
14	NC	I/O	I/O	I/O
15	I/O	I/O	I/O	I/O
16	I/O	I/O	I/O	I/O
17	NC	I/O	I/O	I/O
18	I/O	I/O	I/O	GND
19	I/O	I/O	I/O	V _{CCA}
20	NC	I/O	I/O	I/O
21	I/O	I/O	I/O	I/O
22	I/O	I/O	I/O	I/O
23	NC	I/O	I/O	I/O
24	I/O	I/O	I/O	I/O
25	NC	NC	NC	I/O
26	GND	GND	GND	GND
27	V _{CCA}	V _{CCA}	V _{CCA}	V _{CCA}
28	GND	GND	GND	GND
29	I/O	I/O	I/O	I/O
30	TRST, I/O	TRST, I/O	TRST, I/O	TRST, I/O
31	NC	I/O	I/O	I/O
32	I/O	I/O	I/O	I/O
33	I/O	I/O	I/O	I/O
34	I/O	I/O	I/O	I/O
35	NC	I/O	I/O	I/O

208-Pin PQFP				
Pin Number	A54SX08A Function	A54SX16A Function	A54SX32A Function	A54SX72A Function
36	I/O	I/O	I/O	I/O
37	I/O	I/O	I/O	I/O
38	I/O	I/O	I/O	I/O
39	NC	I/O	I/O	I/O
40	V _{CCI}	V _{CCI}	V _{CCI}	V _{CCI}
41	V _{CCA}	V _{CCA}	V _{CCA}	V _{CCA}
42	I/O	I/O	I/O	I/O
43	I/O	I/O	I/O	I/O
44	I/O	I/O	I/O	I/O
45	I/O	I/O	I/O	I/O
46	I/O	I/O	I/O	I/O
47	I/O	I/O	I/O	I/O
48	NC	I/O	I/O	I/O
49	I/O	I/O	I/O	I/O
50	NC	I/O	I/O	I/O
51	I/O	I/O	I/O	I/O
52	GND	GND	GND	GND
53	I/O	I/O	I/O	I/O
54	I/O	I/O	I/O	I/O
55	I/O	I/O	I/O	I/O
56	I/O	I/O	I/O	I/O
57	I/O	I/O	I/O	I/O
58	I/O	I/O	I/O	I/O
59	I/O	I/O	I/O	I/O
60	V _{CCI}	V _{CCI}	V _{CCI}	V _{CCI}
61	NC	I/O	I/O	I/O
62	I/O	I/O	I/O	I/O
63	I/O	I/O	I/O	I/O
64	NC	I/O	I/O	I/O
65	I/O	I/O	NC	I/O
66	I/O	I/O	I/O	I/O
67	NC	I/O	I/O	I/O
68	I/O	I/O	I/O	I/O
69	I/O	I/O	I/O	I/O
70	NC	I/O	I/O	I/O

176-Pin TQFP	
Pin Number	A54SX32A Function
1	GND
2	TDI, I/O
3	I/O
4	I/O
5	I/O
6	I/O
7	I/O
8	I/O
9	I/O
10	TMS
11	V _{CC1}
12	I/O
13	I/O
14	I/O
15	I/O
16	I/O
17	I/O
18	I/O
19	I/O
20	I/O
21	GND
22	V _{CCA}
23	GND
24	I/O
25	TRST, I/O
26	I/O
27	I/O
28	I/O
29	I/O
30	I/O
31	I/O
32	V _{CC1}
33	V _{CCA}
34	I/O
35	I/O
36	I/O

176-Pin TQFP	
Pin Number	A54SX32A Function
37	I/O
38	I/O
39	I/O
40	I/O
41	I/O
42	I/O
43	I/O
44	GND
45	I/O
46	I/O
47	I/O
48	I/O
49	I/O
50	I/O
51	I/O
52	V _{CC1}
53	I/O
54	I/O
55	I/O
56	I/O
57	I/O
58	I/O
59	I/O
60	I/O
61	I/O
62	I/O
63	I/O
64	PRB, I/O
65	GND
66	V _{CCA}
67	NC
68	I/O
69	HCLK
70	I/O
71	I/O
72	I/O

176-Pin TQFP	
Pin Number	A54SX32A Function
73	I/O
74	I/O
75	I/O
76	I/O
77	I/O
78	I/O
79	I/O
80	I/O
81	I/O
82	V _{CC1}
83	I/O
84	I/O
85	I/O
86	I/O
87	TDO, I/O
88	I/O
89	GND
90	I/O
91	I/O
92	I/O
93	I/O
94	I/O
95	I/O
96	I/O
97	I/O
98	V _{CCA}
99	V _{CC1}
100	I/O
101	I/O
102	I/O
103	I/O
104	I/O
105	I/O
106	I/O
107	I/O
108	GND

176-Pin TQFP	
Pin Number	A54SX32A Function
109	V _{CCA}
110	GND
111	I/O
112	I/O
113	I/O
114	I/O
115	I/O
116	I/O
117	I/O
118	I/O
119	I/O
120	I/O
121	I/O
122	V _{CCA}
123	GND
124	V _{CC1}
125	I/O
126	I/O
127	I/O
128	I/O
129	I/O
130	I/O
131	I/O
132	I/O
133	GND
134	I/O
135	I/O
136	I/O
137	I/O
138	I/O
139	I/O
140	V _{CC1}
141	I/O
142	I/O
143	I/O
144	I/O

256-Pin FBGA			
Pin Number	A54SX16A Function	A54SX32A Function	A54SX72A Function
P15	I/O	I/O	I/O
P16	I/O	I/O	I/O
R1	I/O	I/O	I/O
R2	GND	GND	GND
R3	I/O	I/O	I/O
R4	NC	I/O	I/O
R5	I/O	I/O	I/O
R6	I/O	I/O	I/O
R7	I/O	I/O	I/O
R8	I/O	I/O	I/O
R9	HCLK	HCLK	HCLK
R10	I/O	I/O	QCLKB
R11	I/O	I/O	I/O
R12	I/O	I/O	I/O
R13	I/O	I/O	I/O
R14	I/O	I/O	I/O
R15	GND	GND	GND
R16	GND	GND	GND
T1	GND	GND	GND
T2	I/O	I/O	I/O
T3	I/O	I/O	I/O
T4	NC	I/O	I/O
T5	I/O	I/O	I/O
T6	I/O	I/O	I/O
T7	I/O	I/O	I/O
T8	I/O	I/O	I/O
T9	V _{CCA}	V _{CCA}	V _{CCA}
T10	I/O	I/O	I/O
T11	I/O	I/O	I/O
T12	NC	I/O	I/O
T13	I/O	I/O	I/O
T14	I/O	I/O	I/O
T15	TDO, I/O	TDO, I/O	TDO, I/O
T16	GND	GND	GND